Search Notes

Applica	ation/Control No.	Applicant(s) Reexaminat	/Patent under ion
10/600	,014	CHATTERJ	JEE ET AL.
Exami	ner	Art Unit	
Shew-	Fen Lin	2166	:

SEARCHED					
Class	Subclass	Date	Examiner		
715	512	11/30/2005	SFL		
715	730	11/30/2005	SFL		
707	100	11/30/2005	. SFL		
709	200-250	11/30/2005	SFL		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		- 7,000			

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Palm	11/30/2005	SFL
Plus	11/30/2005	SFL
East (US-PUB, USPAT, USOCR, EPO, JPO, IBM-TDB)	11/30/2005	SFL
Consult with Mohammad Ali	11/30/2005	SFL